

Notice of References Cited	Application/Control No. 10/038,692	Applicant(s)/Patent Under Reexamination CHOU, DAVID	
	Examiner Thu V Huynh	Art Unit 2178	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,715,129	03-2004	Hind et al.	715/513
	B	US-2003/0101203	05-2003	Chen et al.	707/513
	C	US-2002/0095458	07-2002	Silverstein et al.	709/203
	D	US-6,061,738	05-2000	Osaku et al.	709/245
	E	US-2002/0087683	07-2002	Szondy, Gyorgy	709/225
	F	US-2003/0011631	01-2003	Halahmi, Erez	345/744
	G	US-2003/0182449	09-2003	Anderson et al.	709/245
	H	US-2002/0001295	01-2002	Park, Woo-kyeong	370/338
	I	US-6,453,361	09-2002	Morris, Robert Paul	709/250
	J	US-6,430,624	08-2002	Jamtgaard et al.	709/246
	K	US-2004/0024848	02-2004	Smith et al.	709/219
	L	US-2002/0059344	05-2002	BRITTON et al.	707/513
	M	US-2001/0015972	08-2001	Horiguchi et al.	370/352

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	60,251,566
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.